METHOD FOR USING DATA REGARDING MANUFACTURING PROCEDURES INTEGRATED CIRCUITS (IC'S) HAVE UNDERGONE, SUCH AS REPAIRS, TO SELECT PROCEDURES THE IC'S WILL UNDERGO, SUCH AS ADDITIONAL REPAIRS

CROSS-REFERENCE TO RELATED APPLICATIONS

[0001]   This application is a continuation-in-part of application Serial No. 09/292,655, filed April 15, 1999, now U.S. Patent 6,363,295, issued March 26, 2002, which is a continuation of application Serial No. 08/871,015, filed June 6, 1997, now U.S. Patent No. 5,907,492, issued May 25, 1999.

[0002]   This application is related to: an application having Serial No. 08/591,238, filed January 17, 1996, entitled "METHOD AND APPARATUS [sic] FOR STORAGE OF TEST RESULTS WITHIN AN INTEGRATED CIRCUIT", abandoned in favor of a continuation-in-part application filed February 27, 1998, having Serial No. 09/032,417, and entitled "METHOD AND APPARATUS [sic] FOR STORAGE OF TEST RESULTS WITHIN AN INTEGRATED CIRCUIT", now U.S. Patent 6,194,738, issued February 27, 2001; an application having Serial No. 08/664,109, filed June 13, 1996, entitled "A STRUCTURE AND A METHOD FOR STORING INFORMATION IN A SEMICONDUCTOR DEVICE", now U.S. Patent 5,895,962, issued April 20, 1999; an application filed January 17, 1997 having Serial No. 08/785,353 and entitled "METHOD FOR SORTING INTEGRATED CIRCUIT DEVICES", now U.S. Patent 5,927,512, issued July 27, 1999; an application filed February 17, 1997 having Serial No. 08/801,565 and entitled "METHOD OF SORTING A GROUP OF INTEGRATED CIRCUIT DEVICES FOR THOSE DEVICES REQUIRING SPECIAL TESTING",now U.S. Patent 5,844,803, issued December 1, 1998; an application filed February 26, 1997 having Serial No. 08/806,442 and entitled "METHOD IN AN INTEGRATED CIRCUIT (IC) MANUFACTURING PROCESS FOR IDENTIFYING AND RE-DIRECTING IC'S MIS-PROCESSED DURING THEIR MANUFACTURE", now U.S. Patent 5,915,231, issued June 22, 1999; and an application filed March 24, 1997 having Serial No. 08/822,731 and entitled